Technical magazine of Electron Microscope and Analytical Instruments.

**New Products** 

## **ArBlade 5000 Ion-Milling System**

Hitachi has released the "ArBlade 5000", our top of the line ion-milling system for producing exceptional quality cross section or flat-milling samples for electron microscopy. The "ArBlade 5000" is the newest addition to Hitachi's ion-milling system, designed to meet the advanced and high-throughput milling requirements for high-resolution scanning electron microscopy.

The "ArBlade 5000" is equipped with a fast-milling Ar ion gun with a milling rate twice as high as that of the current instrument, thus dramatically reducing the processing time for cross-section milling. Additionally, touch-panel operation enhances the ease of use, which includes an auto-start function. To meet large area milling requirements for electronic device applications, the new cross-section milling holder\* is developed for wider area fabrication. This holder enables higher throughput for not only electronic devices, but also hard materials such as ceramics and composite materials as well.

\*Optional

## Key advantages of the ArBlade 5000

- (1) New fast-milling Ar ion gun (cross-section milling rate : 1 mm/hr or faster)
- (2) Optional holder for wide-area cross-section milling, allowing milling of samples up to 8 mm in width.
- (3) New and improved operating interface with an LCD touch panel.
- (4) Hybrid ion-milling system supporting both cross-section milling and Flat milling.



ArBlade 5000 Ion-Milling System